



High Speed Super Low Power SRAM

512K Words By 8 Bit

CS18LV41965

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GENERAL DESCRIPTION

The CS18LV41965 is a high performance, high speed, and super low power CMOS Static Random Access Memory organized as 524,288 words by 8 bits and operates from a wide range of 4.5 to 5.5V supply voltage. Advanced 0.15um CMOS technology and circuit techniques provide both high speed and low power features with a typical CMOS standby current of 5uA and maximum access time of 45/55/70ns in 5.0V operation.

The CS18LV41965 has an automatic power down feature, reducing the power consumption significantly when chip is deselected. The CS18LV41965 is available in JEDEC standard 32-pin sTSOP 1 -8x13.4 mm, TSOP 1 -8x20mm, TSOP 2 -400mil packages.

FEATURES

- Low operation voltage: 4.5 ~ 5.5V
- Ultra low power consumption :
 - operating current: 22mA (Max.) @ $t_{AA}=45ns$
 - standby current: 5uA (Typ.)
- Fast access time: 45/55/70ns (Max.)
- Automatic power down when chip is deselected.
- Three state outputs and TTL compatible, fully static operation
- Data retention supply voltage as low as 2.0V.

Product Family

Product Family	Operating Temp	Standby (Max.) (Vcc = 5.5V)	Vcc. Range (V)	Speed (ns)	Package Type
CS18LV41965	0~70°C	11uA	4.5~5.5	45/55/70	32L STSOP 1
	-40~85°C	16uA			32L TSOP 1 32L TSOP 2

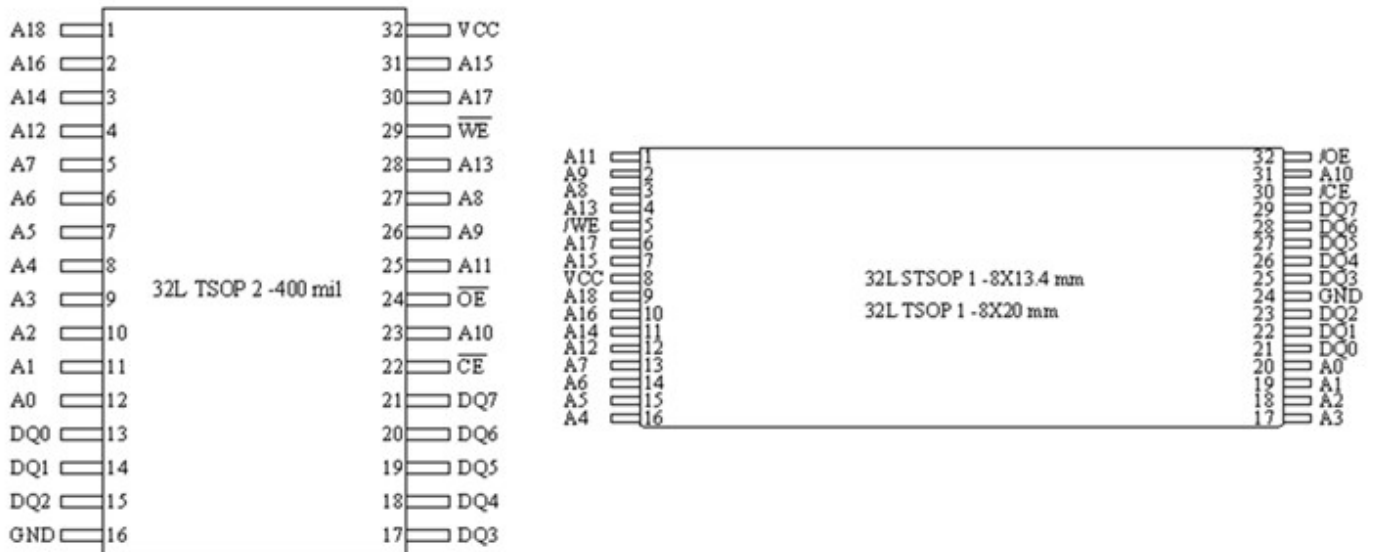


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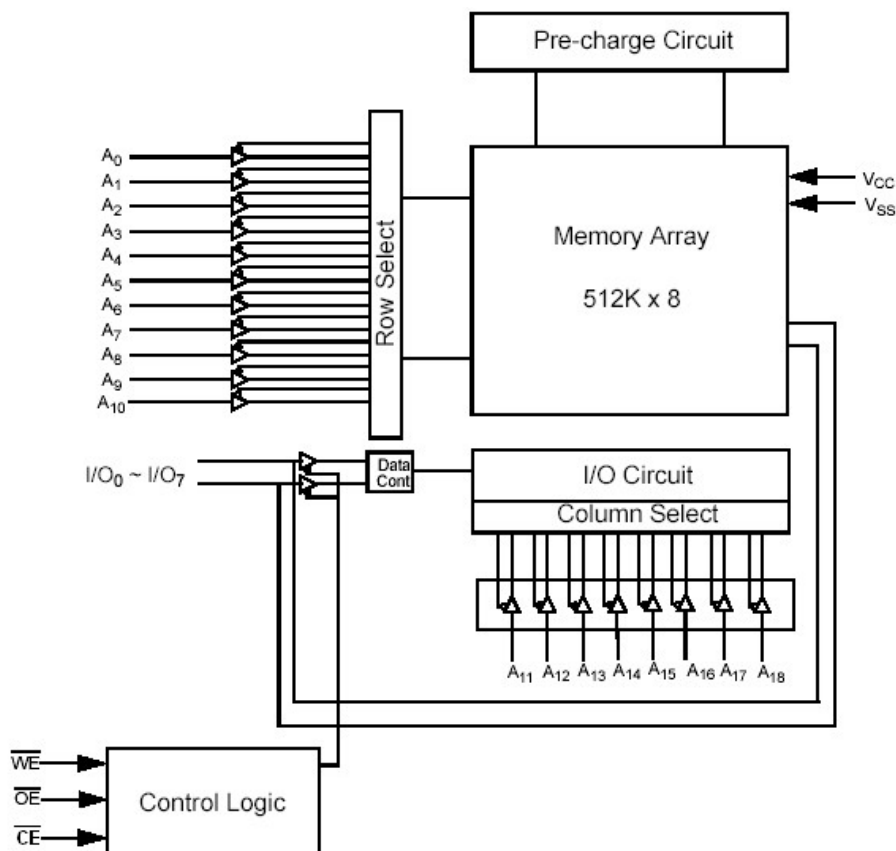
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PIN CONFIGURATIONS



FUNCTIONAL BLOCK DIAGRAM





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PIN DESCRIPTIONS

Name	Type	Function
A0 – A18	Input	Address inputs for selecting one of the 524,288 x 8 bit words in the RAM
/CE	Input	/CE is active LOW. Chip enables must be active when data read from or write to the device. If either chip enable is not active, the device is deselected and in a standby power down mode.
/WE	Input	The Write enable input is active LOW. It controls read and write operations. With the chip selected, when /WE is HIGH and /OE is LOW, output data will be present on the DQ pins, when /WE is LOW, the data present on the DQ pins will be written into the selected memory location.
/OE	Input	The output enable input is active LOW. If the output enable is active while the chip is selected and the write enable is inactive, data will be present on the DQ pins and they will be enabled.
DQ0~DQ7	I/O	These 8 bi-directional ports are used to read data from or write data into the RAM.
Vcc	Power	Power Supply
Vss	Power	Ground
NC		No connection

TRUTH TABLE

MODE	/CE	/WE	/OE	DQ0~7	Vcc Current
Standby	H	X	X	High Z	I _{CCSB} , I _{CCSB1}
Output Disabled	L	H	H	High Z	I _{CC}
Read	L	H	L	D _{OUT}	I _{CC}
Write	L	L	X	D _{IN}	I _{CC}

Note: X means don't care. (Must be low or high state)



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ABSOLUTE MAXIMUM RATINGS ⁽¹⁾

Symbol	Parameter	Rating	Unit
V _{IN} , V _{OUT}	Voltage on any pin relative to V _{SS}	-0.5 to V _{CC} +0.5V	V
V _{CC}	Voltage on V _{CC} supply relative to V _{SS}	-0.5 to 7.0	V
P _D	Power Dissipation	1.5	W

1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

OPERATING RANGE

Range	Ambient Temperature	V _{CC}
Commercial	0~70°C	4.5V ~ 5.5V
Industrial	-40~85°C	4.5V ~ 5.5V

CAPACITANCE ⁽¹⁾ (T_A = 25°C, f = 1.0 MHz)

Symbol	Parameter	Conditions	MAX.	Unit
C _{IN}	Input Capacitance	V _{IN} =0V	6	pF
C _{DQ}	Input/output Capacitance	V _{I/O} =0V	8	pF

1. This parameter is guaranteed and not tested.



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DC ELECTRICAL CHARACTERISTICS ($T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

Parameter Name	Parameter	Test Conduction	MIN	TYP ⁽¹⁾	MAX	Unit
V_{IL}	Guaranteed Input Low Voltage ⁽³⁾	$V_{CC}=5\text{V}$	-0.3		0.8	V
V_{IH}	Guaranteed Input High Voltage ⁽²⁾	$V_{CC}=5\text{V}$	2.2		$V_{CC}+0.5$	V
I_{IL}	Input Leakage Current	$V_{CC}=\text{MAX}$, $V_{IN}=0$ to V_{CC}	-1		1	μA
I_{OL}	Output Leakage Current	$V_{CC}=\text{MAX}$, $/\text{CE}=V_{IH}$, or $/\text{OE}=V_{IH}$, or $/\text{WE}=V_{IL}$, $V_{IO}=0\text{V}$ to V_{CC}	-1		1	μA
V_{OL}	Output Low Voltage	$V_{CC}=\text{MAX}$, $I_{OL} = 2.1\text{mA}$			0.4	V
V_{OH1}	Output High Voltage	$V_{CC}=\text{MIN}$, $I_{OH} = -1.0\text{mA}$	2.4			V
I_{CC}	Operating Power Supply Current	$/\text{CE}=V_{IL}$, $I_{IO}=0\text{mA}$, $F=F_{\text{MAX}}^{(3)}$, 100%duty, $V_{IN}=V_{IL}$ or V_{IH}	45ns		22	mA
			55ns		22	
			70ns		20	
I_{CCSB}	Standby Supply - TTL	$/\text{CE}=V_{IH}$, $I_{UO}=0\text{mA}$, other pins= V_{IL} or V_{IH}			5	mA
I_{CCSB1}	Standby Current -CMOS	$/\text{CE}\geq V_{CC}-0.2\text{V}$, $V_{IN}\geq V_{CC}-0.2\text{V}$ or $V_{IN}\leq 0.2\text{V}$	25°C	5	8	μA
			70°C		11	
			85°C		16	

1. Typical characteristics are measured at $V_{CC}=5\text{V}$, $T_A=25^\circ\text{C}$ and not 100% tested

2. Overshoot: $V_{CC} + 2.0\text{V}$ in case of pulse width $\leq 20\text{ns}$.

3. Undershoot: -2.0V in case of pulse width $\leq 20\text{ns}$.

4. Overshoot and undershoot are sampled, not 100% tested.



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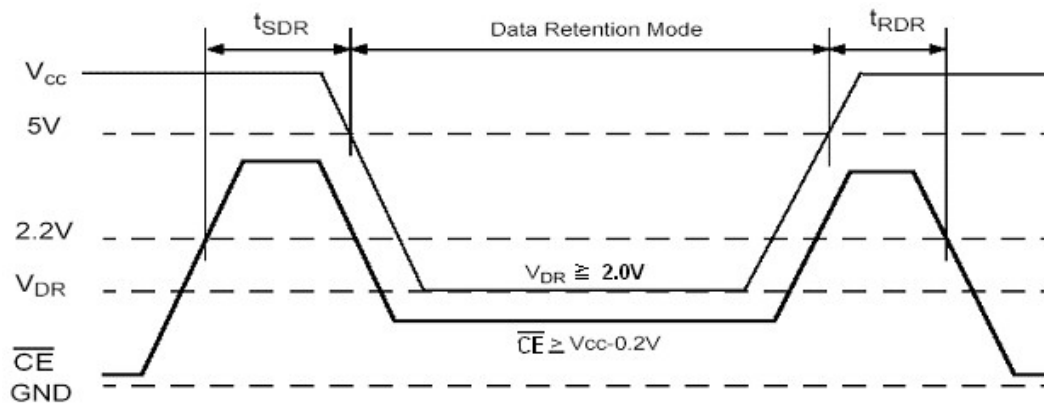
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DATA RETENTION CHARACTERISTICS($T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$)

Parameter Name	Parameter	Test Conduction	MIN	TYP	MAX	Unit
V_{DR}	V_{CC} for Data Retention	$/CE \geq V_{CC}-0.2V$, $V_{IN} \geq V_{CC}-0.2V$ or $V_{IN} \leq 0.2V$	2			V
I_{CCDR}	Data Retention Current	$/CE \geq V_{CC}-0.2V$, $V_{CC}=2.0V$ $V_{IN} \geq V_{CC}-0.2V$ or $V_{IN} \leq 0.2V$		5	16	μA
t_{SDR}	Chip Deselect to Data Retention Time	See Retention Waveform	0			ns
t_{RDR}	Operation Recovery Time		t_{RC}			ns

LOW V_{CC} DATA RETENTION WAVEFORM(/CE Controlled)





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AC TEST CONDITIONS

Input Pulse Levels: $V_{CC}/0V$

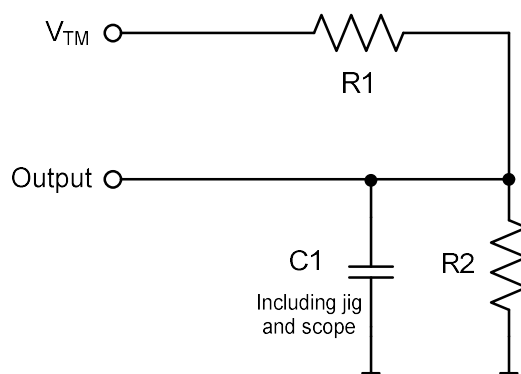
Input Rise and Fall Times: 3ns

Input and Output Timing Reference Level: 0.5 V_{CC}

Output Load (See right):

CL: 30pF + 1 TTL, $I_{OH}/I_{OL} = -1mA/2.1mA$

$R1=1800\Omega$, $R2=990\Omega$. $V_{TM} = V_{CC}$



KEY TO SWITCHING WAVEFORMS

WAVEFORMS	INPUTS	OUTPUTS
	MUST BE STEADY	MUST BE STEADY
	MAY CHANGE FROM H TO L	WILL BE CHANGE FROM H TO L
	MAY CHANGE FROM L TO H	WILL BE CHANGE FROM L TO H
	DON'T CARE ANY CHANGE PERMITTED	CHANGE STATE UNKNOWN
	DOES NOT APPLY	CENTER LINE IS HIGH IMPEDANCE OFF STATE

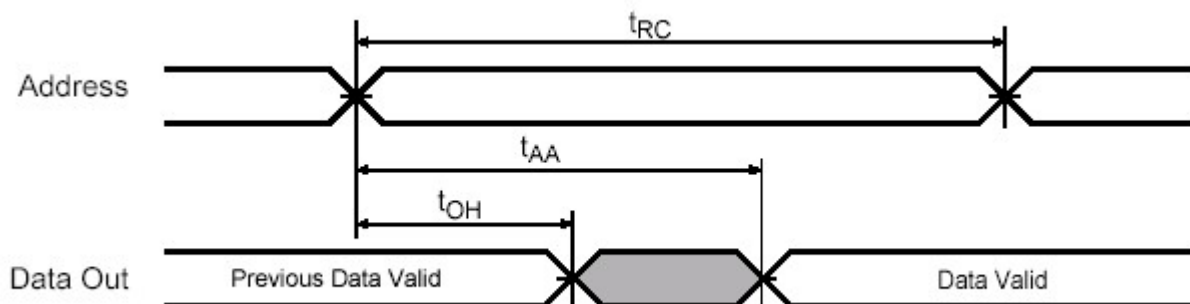
AC ELECTRICAL CHARACTERISTICS($T_A = 0^{\circ}C$ to $+70^{\circ}C$, $V_{CC} = 5.0V$)

[READ CYCLE]

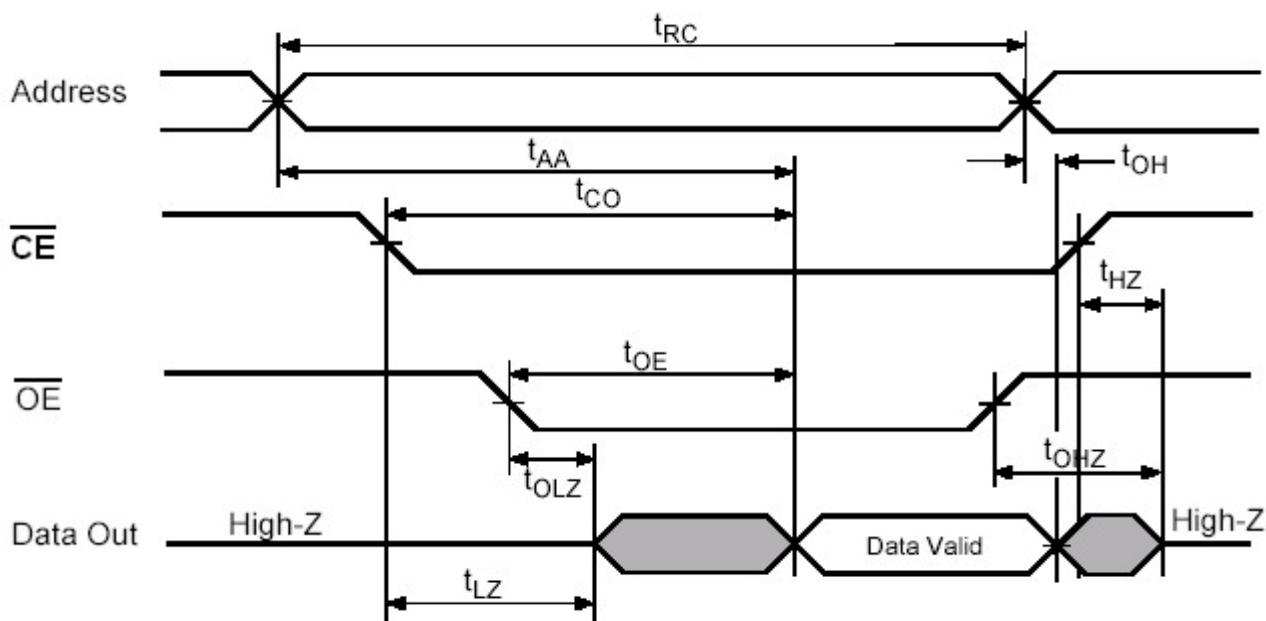
JEDEC Name	Parameter Name	Description	45ns		55ns		70ns		Unit
			MIN	MAX	MIN	MAX	MIN	MAX	
t_{AVAX}	t_{RC}	Read Cycle Time	45		55		70		ns
t_{AVQV}	t_{AA}	Address Access Time		45		55		70	ns
t_{ELQV}	t_{CO}	Chip Select Access Time (/CE)		45		55		70	ns
t_{GLQV}	t_{OE}	Output Enable to Output Valid		20		25		35	ns
t_{ELQX}	t_{LZ}	Chip Select to Output Low Z (/CE)	5		5		5		ns
t_{GLQX}	t_{OLZ}	Output Enable to Output in Low Z	5		5		5		ns
t_{EHQZ}	t_{HZ}	Chip Deselect to Output in High Z (/CE)		15		15		15	ns
t_{GHQZ}	t_{OHZ}	Output Disable to Output in High Z		15		15		15	ns
t_{AXOX}	t_{OH}	Out Disable to Address Change	10		10		10		ns

SWITCHING WAVEFORMS (REAS CYCLE)

READ CYCLE(1) (Address Transition Controlled)



READ CYCLE(2) (/OE Controlled)



NOTES:

1. t_{HZ} and t_{OHZ} are defined as the outputs achieve the open circuit conditions and are not referenced to output voltage levels.
2. At any given temperature and voltage condition, t_{HZ} (Max.) is less than t_{LZ} (Min.) both for a given device and from device to device interconnection.



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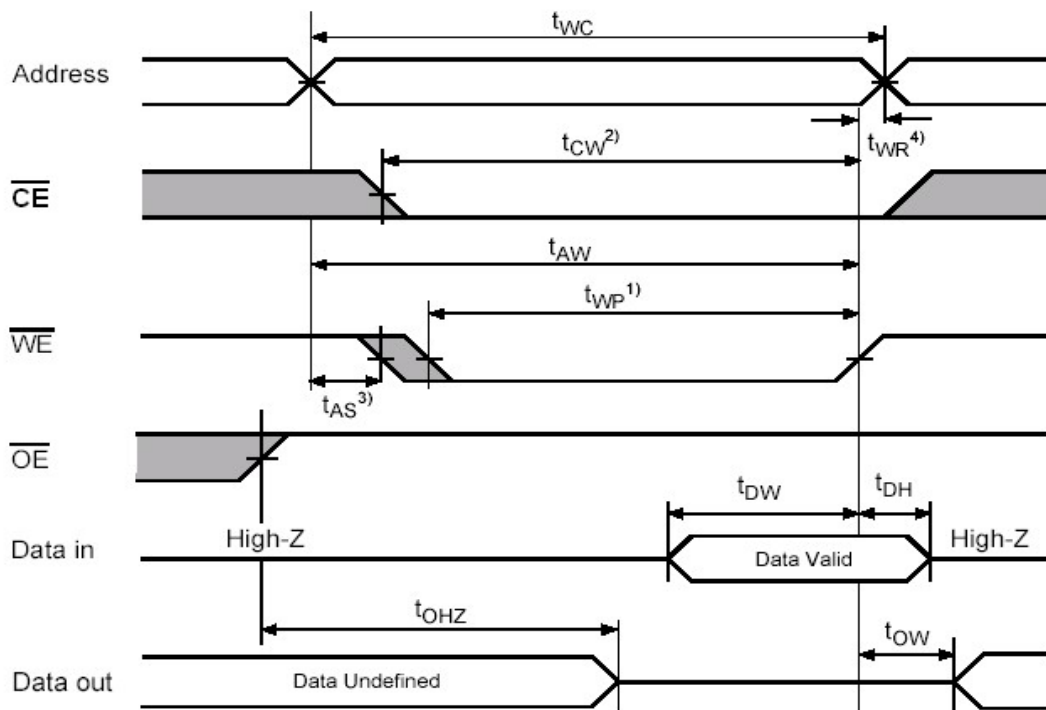
AC ELECTRICAL CHARACTERISTICS ($T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

[WRITE CYCLE]

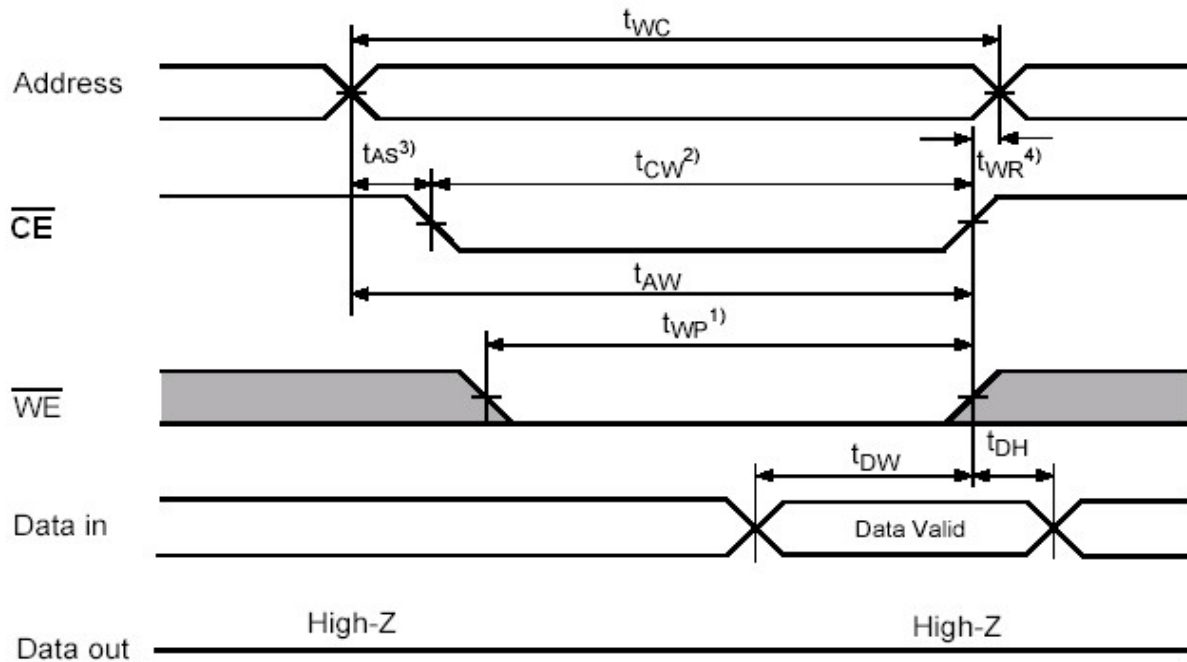
JEDEC Name	Parameter Name	Description	45ns		55ns		70ns		Unit
			MIN	MAX	MIN	MAX	MIN	MAX	
t_{AVAX}	t_{WC}	Write Cycle Time	45		55		70		ns
t_{E1LWH}	t_{CW}	Chip Select to End of Write	35		35		50		ns
t_{AVWL}	t_{AS}	Address Setup Time	0		0		0		ns
t_{AVWH}	t_{AW}	Address Valid to End of Write	35		35		50		ns
t_{WLWH}	t_{WP}	Write Pulse Width	35		35		50		ns
t_{WHAX}	t_{WR}	Write Recovery Time (/CE, /WE)	0		0		0		ns
t_{WLQZ}	t_{WHZ}	Write to Output in High Z		15		15		25	ns
t_{DVWH}	t_{DW}	Data to Write Time Overlap	20		25		30		ns
t_{WHDX}	t_{DH}	Data Hold from Write Time	0		0		0		ns
t_{WHOX}	t_{OW}	End of Write to Output Active	5		5		5		ns

SWITCHING WAVEFORMS(WRITE CYCLE)

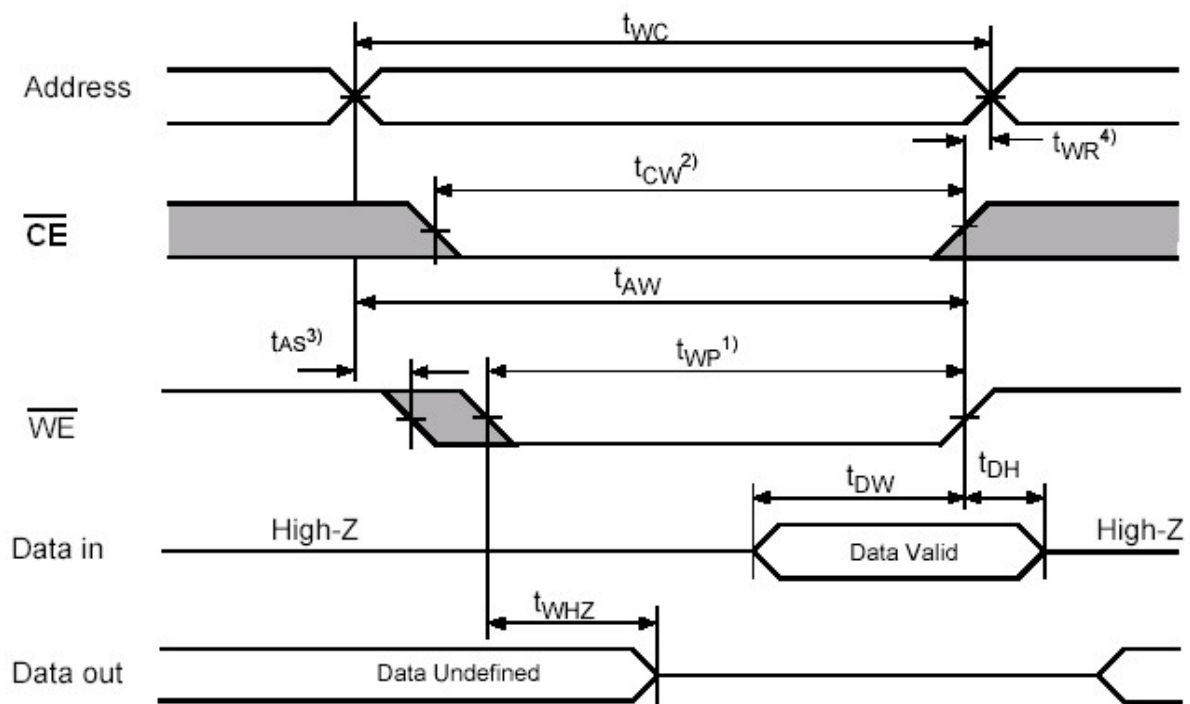
WRITE CYCLE(1) (/WE Controlled, /OE High During WRITE)



WRITE CYCLE(2) (/CE Controlled)



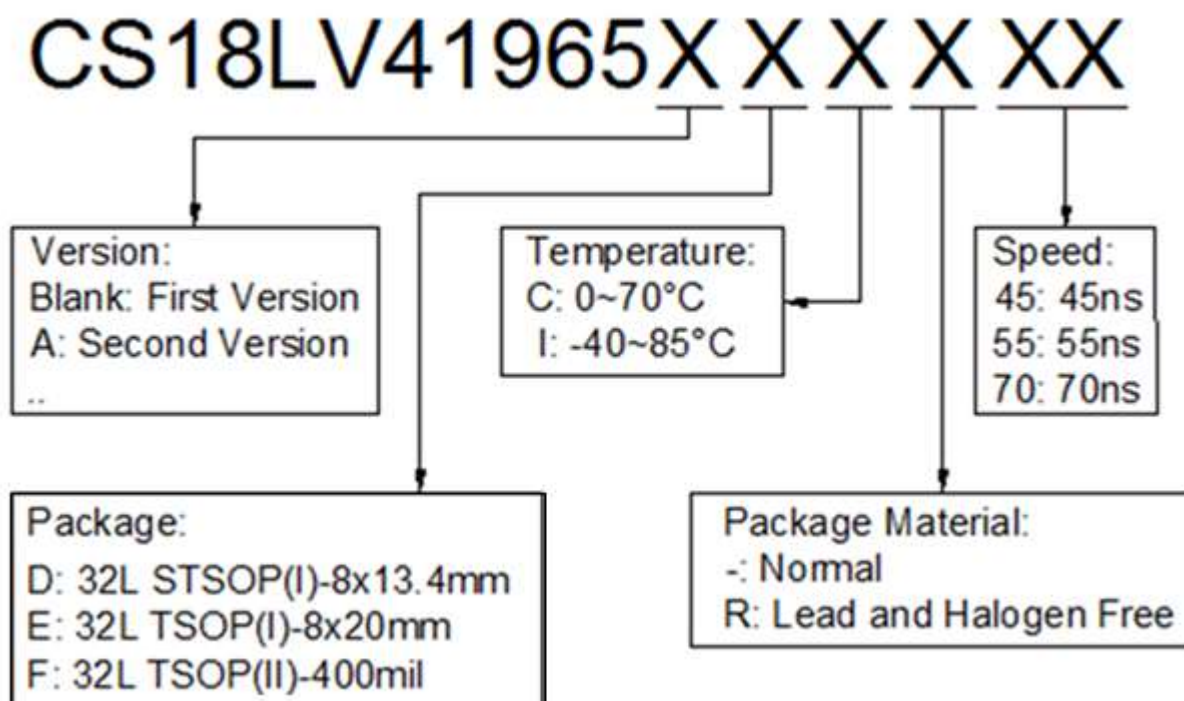
WRITE CYCLE(3) (/WE Controlled, /OE LOW)



NOTES:

1. A write occurs during the overlap (t_{WP}) of low $/CE$ and low $/WE$. A write begins at the latest transition among $/CE$ goes low and $/WE$ goes low. A write ends at the earliest transition when $/CE$ goes high and $/WE$ goes high. The t_{WP} is measured from the beginning of write to the end of write.
2. t_{CW} is measured from the $/CE$ going low to end of write.
3. t_{AS} is measured from the address valid to the beginning of write.
4. t_{WR} is measured from the end of write to the address change. t_{WR} applied in case a write ends as $/CE$ or $/WE$ going high.

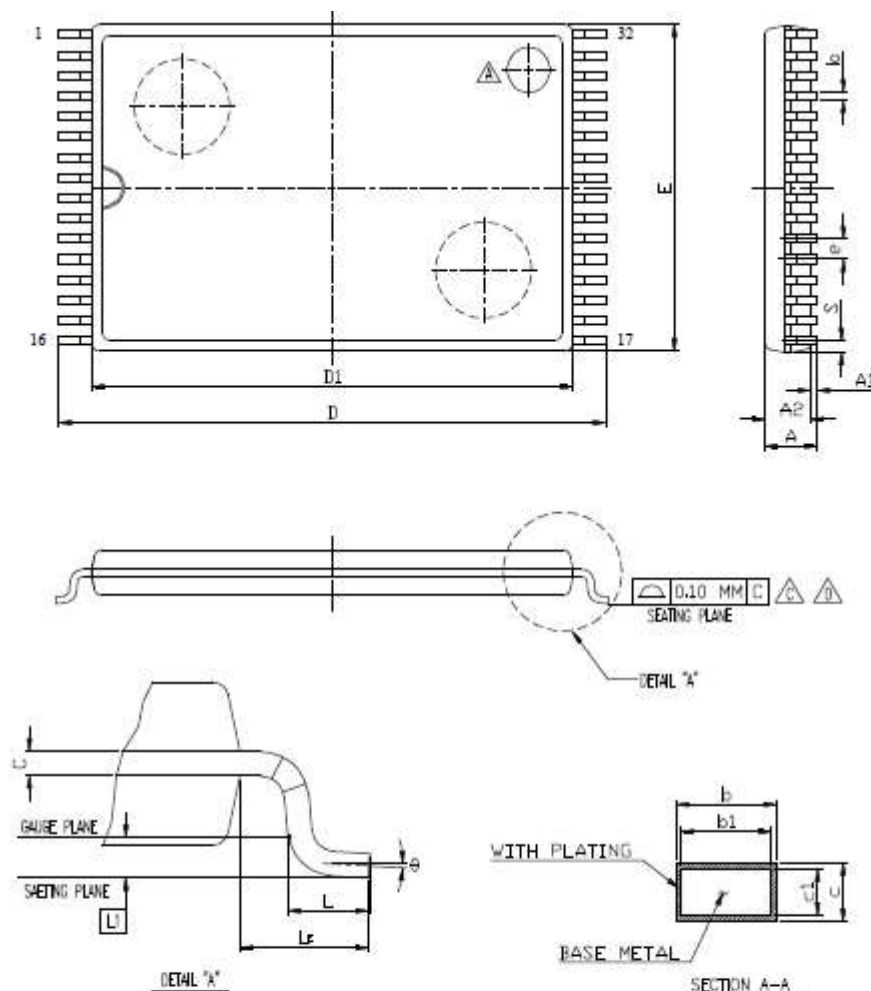
ORDER INFORMATION



Note: Package material code "R" meets ROHS

PACKAGE OUTLINE

32L STSOP (I)-8x13.4mm

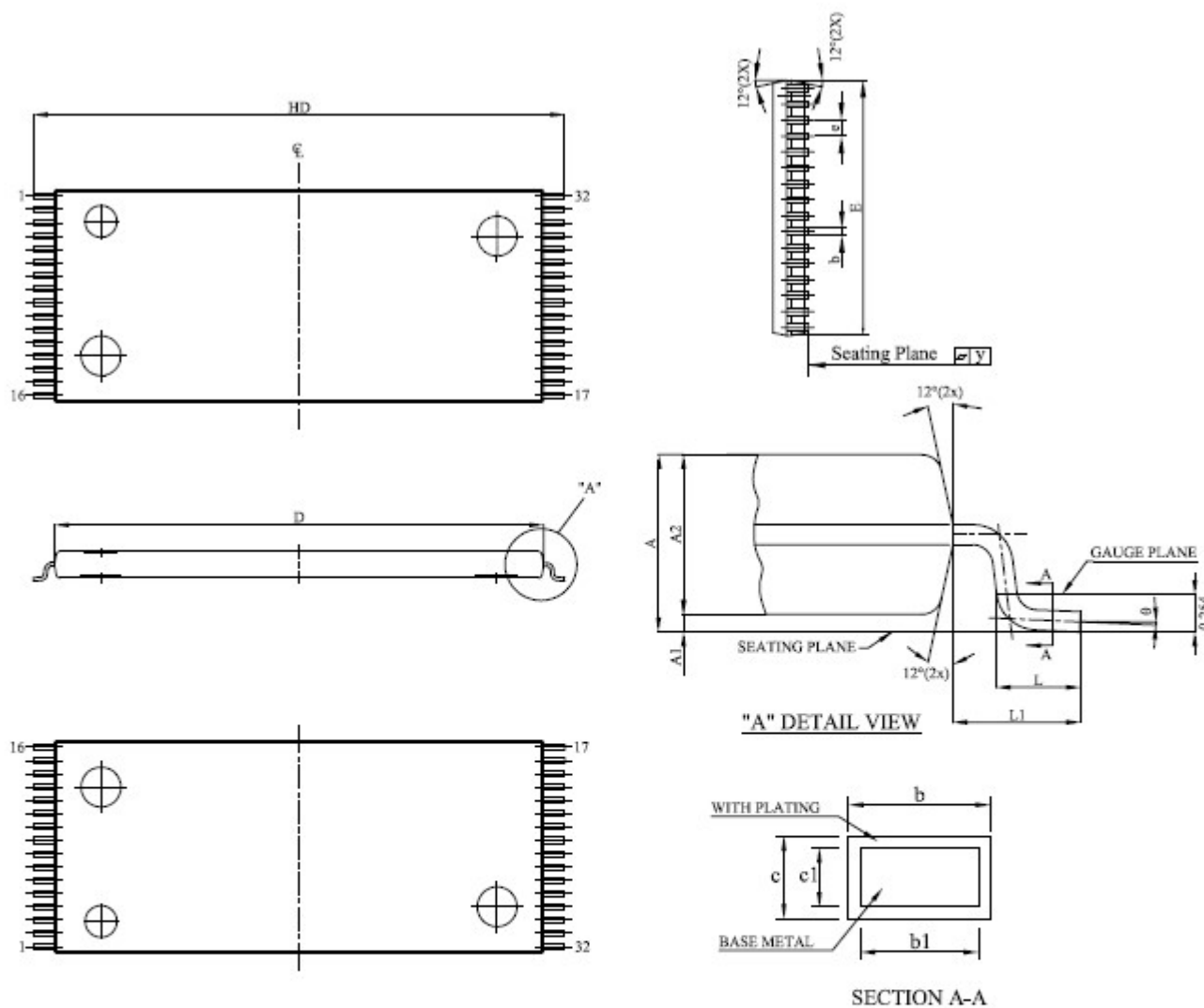


Note: Dimensions D1 and E do not include mold protrusions.

D1 and E are maximum plastic body size dimensions including mold mismatch.

SYMBOL UNIT		A	A1	A2	b	b1	c	c1	E	e	D	D1	L	L1	LE	S	e
mm	Min.		0.05	0.90	0.17	0.17	0.10	0.10	7.90	0.50 TYP.	13.20	11.70	0.30	0.25 BSC	0.675	0.278 TYP.	0
	Nom.			1.00	0.22	0.20	-	-	8.00		13.40	11.80	0.50				3
	Max.	1.20		1.05	0.27	0.23	0.21	0.16	8.10		13.60	11.90	0.70				5
inch	Min.		0.002	0.035	0.007	0.007	0.004	0.004	0.311	0.020 TYP.	0.520	0.461	0.012	0.010 BSC	0.027	0.0109 TYP.	0
	Nom.			0.039	0.009	0.008	-	-	0.315		0.528	0.465	0.020				3
	Max.	0.047		0.041	0.011	0.009	0.008	0.006	0.319		0.535	0.469	0.028				5

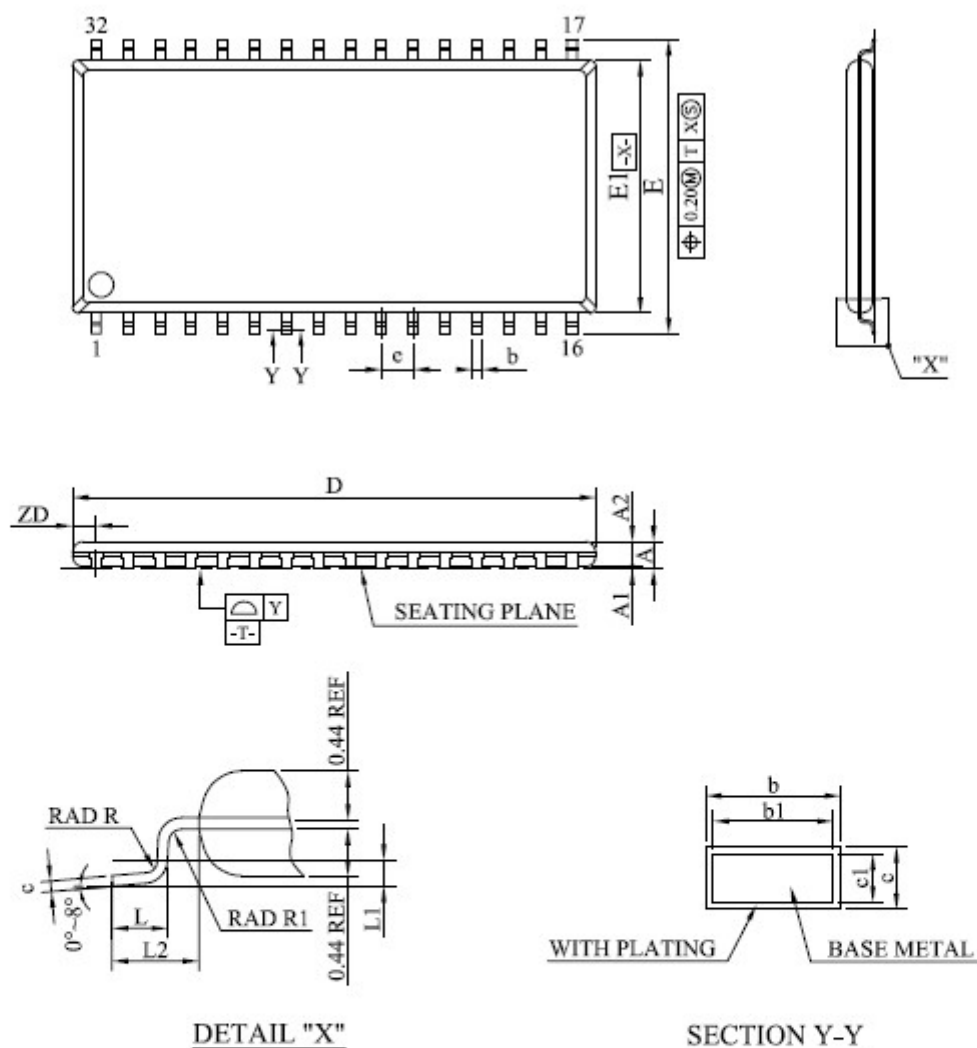
32L TSOP (I)-12x20mm



Note: Plating thickness spec : 0.3 mil ~ 0.8 mil.

SYMBOL UNIT		A	A1	A2	b	b1	c	c1	D	E	e	HD	L	L1	y	Θ
mm	Min.	1.00	0.05	0.95	0.17	0.17	0.10	0.10	18.30	7.90	0.40	19.80	0.40	0.70	—	0°
	Nom.	1.10	0.10	1.00	0.22	0.20	—	—	18.40	8.00	0.50	20.00	0.50	0.80	—	—
	Max.	1.20	0.15	1.05	0.27	0.23	0.21	0.16	18.50	8.10	0.60	20.20	0.70	0.90	0.1	8°
inch	Min.	0.0393	0.002	0.037	0.007	0.007	0.004	0.004	0.720	0.311	0.016	0.779	0.0157	0.0275	—	0°
	Nom.	0.0433	0.004	0.039	0.009	0.008	—	—	0.724	0.315	0.020	0.787	0.0197	0.0315	—	—
	Max.	0.0473	0.006	0.041	0.011	0.009	0.008	0.006	0.728	0.319	0.024	0.795	0.0277	0.0355	0.004	8°

32L TSOP2-400mil



Note: Plating thickness spec : 0.3 mil ~ 0.8 mil.

SYMBOL	UNIT	A	A1	A2	b	b1	c	c1	D	E	E1	e	L	L1	L2	R	R1	ZD	Y
mm	Min.	—	0.05	0.95	0.30	0.30	0.12	0.10	20.82	11.56	10.03	1.27 bsc	0.40	0.25 bsc	0.8 ref	0.12	0.12	0.95 ref	—
	Nom.	—	0.10	1.00	—	0.40	—	0.127	20.95	11.76	10.16		0.50			—	—		—
	Max.	1.20	0.15	1.05	0.52	0.45	0.21	0.16	21.08	11.96	10.29		0.60			0.25	—		0.10
inch	Min.	—	0.002	0.037	0.012	0.012	0.005	0.004	0.820	0.455	0.394	0.050 bsc	0.016	0.010 bsc	0.031 ref	0.005	0.005	0.037 ref	—
	Nom.	—	0.004	0.039	—	0.016	—	0.005	0.825	0.463	0.400		0.020			—	—		—
	Max.	0.047	0.006	0.042	0.020	0.018	0.008	0.006	0.830	0.471	0.405		0.024			0.010	—		0.004